


<b>Search Notes</b>  	<b>Application/Control No.</b>  10826415	<b>Applicant(s)/Patent Under Reexamination</b>  DOEPKE ET AL.
	<b>Examiner</b>  RACHNA S DESAI	<b>Art Unit</b>  2176

SEARCHED			
Class	Subclass	Date	Examiner
715	201	08/12/10	RSD
725	47, 86	08/12/10	RSD

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM-TDB) - Search Notes Attached	08/12/10	RSD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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